

NeoScope™ JCM-7000Plus



“Observe Now. Act Next” Live Observation, Evolved

NeoScope™ JCM-7000Plus

The JCM-7000Plus benchtop SEM transforms routine observation into immediate insight. By combining high-quality SEM imaging with real-time elemental analysis and automated workflows, this benchtop SEM helps users quickly understand their samples and move confidently to the next step.

Whether screening materials, investigating defects, or performing quality control, the JCM-7000Plus delivers the information you need—when you need it.

Real-Time Insight with Four Live Functions

Gain immediate understanding of your specimen while you observe.

New!

Live Particle

Automatically measures particle and feature sizes in real time, eliminating manual measurement steps.



Specimen: Silicon oxides particles

Live Analysis

Provides immediate elemental identification, allowing rapid decision-making without interrupting your workflow.



Specimen: Alloy



Live 3D

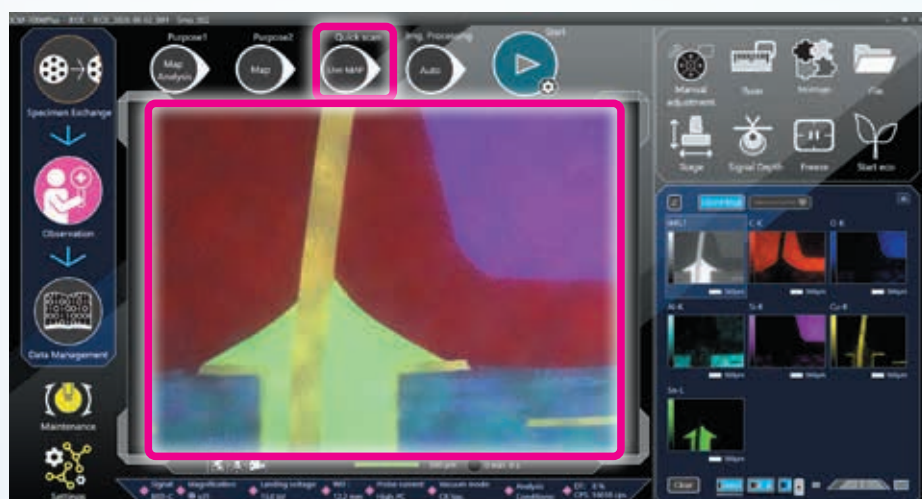
Instantly reveals surface topography, providing a deeper understanding of sample morphology.



Specimen: Metal fracture surface

Live Map

Visualizes elemental distribution across the field of view as you observe, helping identify compositional variations faster.



Specimen: Electronic component cross-section

Automated Workflows for Greater Productivity

Turn observation into action with intelligent automation designed to improve both throughput and consistency.

Auto Image Optimization

Automatically adjusts contrast and brightness, focus, and astigmatism to produce high-quality images with minimal user intervention.

Feature Introduction Video

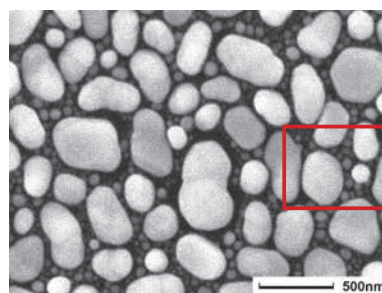


Specimen: Tin particles

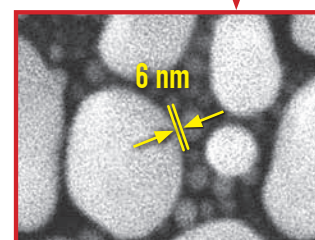
New!

Accelerating Voltages up to 20 kV

Accelerating voltages up to 20 kV provide flexibility for a wide range of applications.



Specimen: Gold particles
AccV. 20 kV
Mag. x50,000



Update!

NeoAction

Automates image acquisition, EDS analysis, and report generation based on predefined workflows. Multiple fields of view can be included, enabling efficient and repeatable analyses.



Specimen: BGA-mounted PCB

Specifications

Resolution	6.0nm (20kV, WD12mm, High-vacuum mode, Secondary electron image) 8.0nm (20kV, WD12mm, High-vacuum mode, Backscattered electron image)
Direct magnification	x10 to 100,000 Magnification is defined by 128 mm x 96 mm
Mode	High-Vacuum mode: Secondary electron image, Backscattered electron image (composition, topographic and shadow, 3D images) Low-Vacuum mode: Backscattered electron image (composition, topographic and shadow, 3D images)
Landing voltage	5kV, 10kV, 15kV, Landing voltage 20kV (4 stages)
Electron source	Tungsten filament/ Wehnelt integrated grid
Specimen stage	X-Y motor drive stage X : 40 mm Y : 40 mm
Maximum specimen size	80 mm diameter x 50 mm height

* Specifications and appearance are subject to change without notice.

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